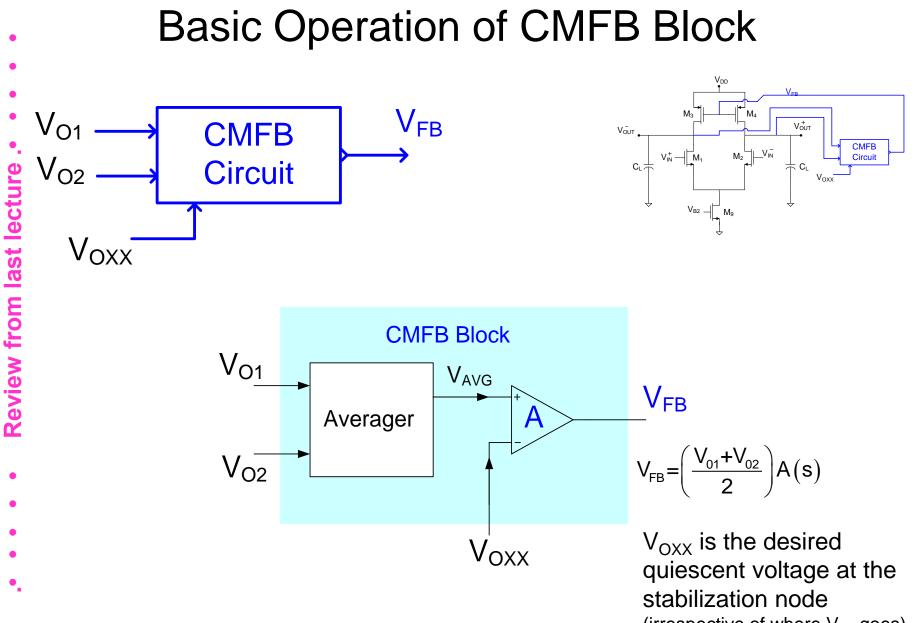
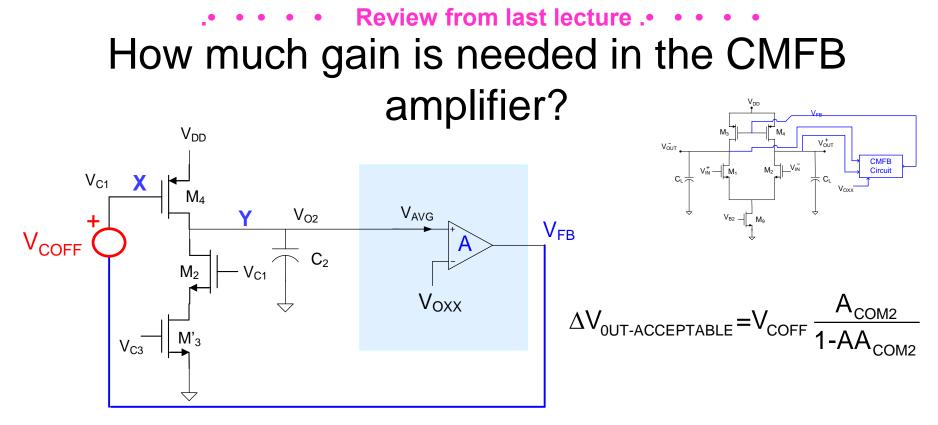
EE 435

Lecture 24

Data Converter Operation



(irrespective of where V_{FB} goes)



The CMFB Loop

- This does not require a particularly large gain
- This is the loop that must be compensated since A and A_{COMP2} will be frequency dependent
- Miller compensation capacitor for compensation of differential loop will often appear in shunt with C₂
- Can create this "half-circuit" loop (without CM inputs on a fully differential structure) for simulations
- Results extend readily to two-stage structures with no big surprises
- Capacitances on nodes X and Y create poles for CMFB circuit
- Reasonably high closed-loop CMFB bandwidth needed to minimize shifts in output due to high-frequency common-mode noise

• • • • • Review from last lecture .• • • •

CMFB Block

Averager

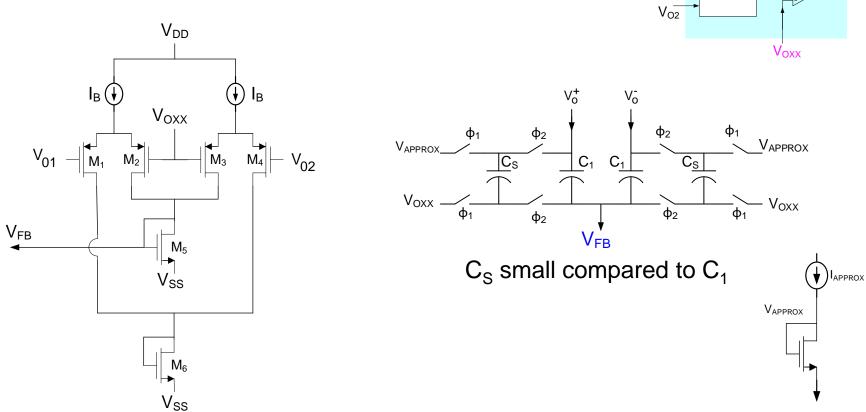
VAVG

VFB

Voi

CMFB Circuits

- Several (but not too many) CMFB blocks are widely used
- Can be classified as either continuous-time or discrete-time



- V_{OXX} generated by simple bias generator
- ϕ_1 and ϕ_2 are complimentary non-overlapping clocks that run continuously

Data Converters

Types:

A/D (Analog to Digital)
Converts Analog Input to a Digital Output
D/A (Digital to Analog)
Converts a Digital Input to an Analog Output

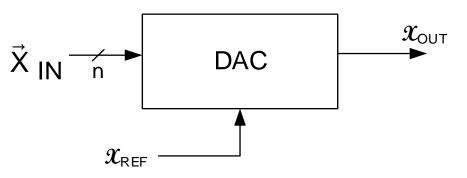
A/D is the world's most widely used mixed-signal component

D/A is often included in a FB path of an A/D

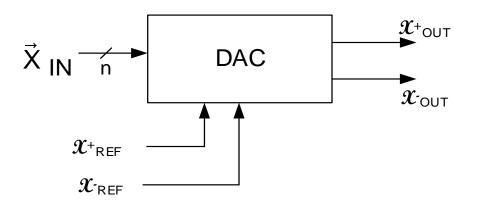
A/D and D/A fields will remain hot indefinitely technology advances make data converter design more challenging embedded applications designs often very application dependent

D/A Converters

Basic structure:

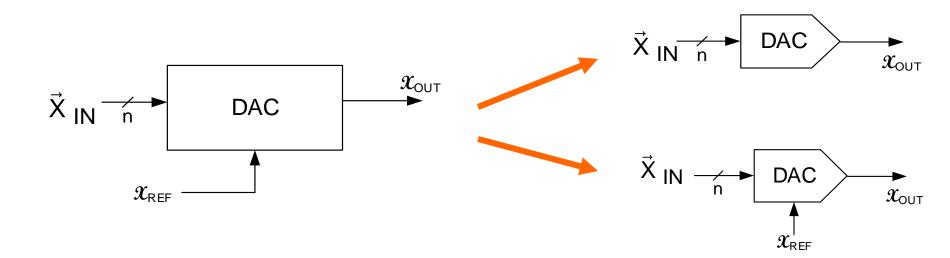


Basic structure with differential outputs::



D/A Converters

Notation:



D/A Converters



 $\vec{X}_{IN} = \langle b_{n-1}, b_{n-1}, \dots, b_1, b_0 \rangle$

b₀ is the Least Significant Bit (LSB)

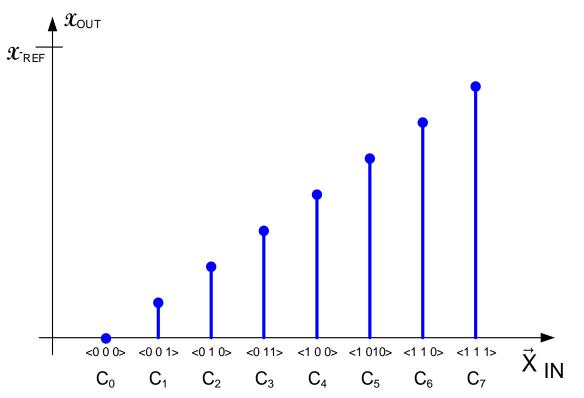
b_{n-1} is the Most Significant Bit (MSB)

Note: some authors use different index notation

An Ideal DAC is characterized at low frequencies by its static performance

D/A Converters \vec{x}_{IN} $\vec{X}_{IN} = \langle b_{n-1}, b_{n-1}, \dots, b_1, b_0 \rangle$

An Ideal DAC transfer characteristic (3-bits)



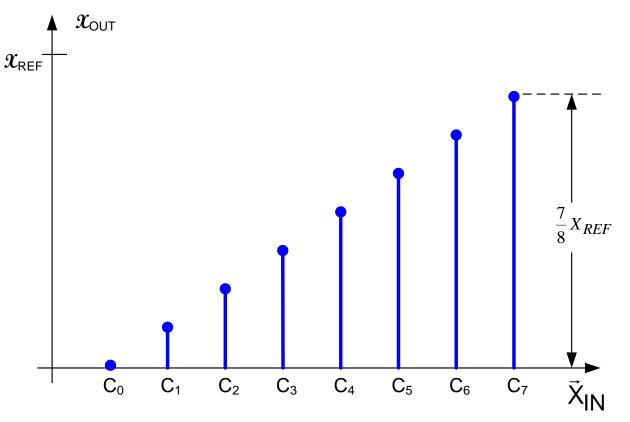
DAC

 $\mathfrak{X}_{\mathsf{OUT}}$

Code C_k is used to represent the decimal equivalent of the binary number $\langle b_{n-1} ... b_0 \rangle$

D/A Converters \vec{x}_{IN} $\vec{X}_{IN} = < b_{n-1}, b_{n-1}, \dots, b_1, b_0 >$

An Ideal DAC transfer characteristic (3-bits)

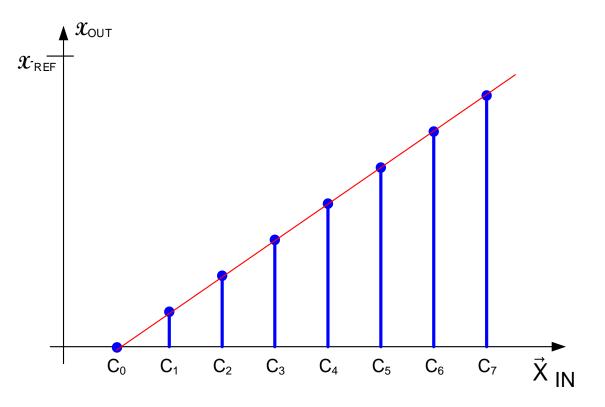


DAC

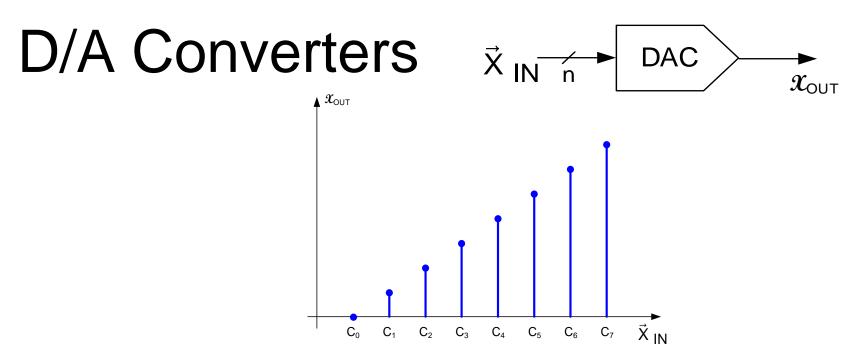
 $\mathcal{X}_{\mathsf{OUT}}$

D/A Converters \vec{x}_{IN} DAC $\mathcal{X}_{\mathsf{OUT}}$ $\vec{X}_{IN} = < b_{n-1}, b_{n-1}, \dots, b_1, b_0 >$

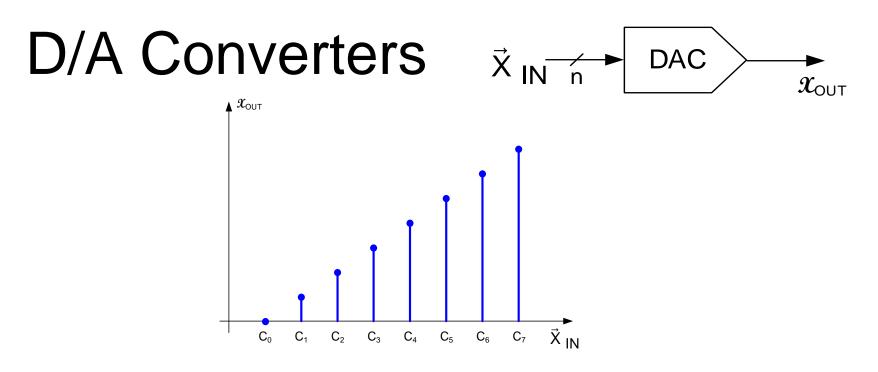
An Ideal DAC transfer characteristic (3-bits)



All points of this ideal DAC lie on a straight line



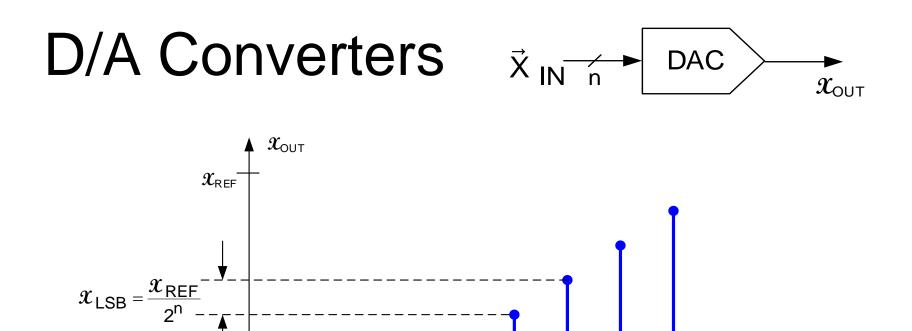
- Most D/A ideally have a linear relationship between binary input and analog output
- Output represents a discrete set of continuous variables
- Typically this number is an integral power of 2, i.e. 2ⁿ
- \vec{X}_{IN} is always dimensionless
- \mathcal{X}_{OUT} could have many different dimensions
- An ideal nonlinear characteristic is also possible (waveform generation and companding)
- Will assume a linear transfer characteristic is desired unless specifically stated to the contrary



For this ideal DAC

$$\begin{aligned} & x_{OUT} = X_{REF} \left(\frac{b_{n-1}}{2} + \frac{b_{n-2}}{4} + \frac{b_{n-3}}{8} + \dots + \frac{b_1}{2^{n-1}} + \frac{b_0}{2^n} \right) \\ & x_{OUT} = X_{REF} \sum_{j=1}^{n} \frac{b_{n-j}}{2^j} \end{aligned}$$

- Number of outputs gets very large for n large
- Spacing between outputs is $X_{REF}/2^n$ and gets very small for n large



 \vec{X}_{IN}

- Ideal steps all equal and termed the LSB
- $\mathcal{X}_{\rm LSB}$ gets very small for small $\mathcal{X}_{\rm REF}$ and large n

 C_0

 C_1

e.g. If $\mathcal{X}_{REF}=1V$ and n=16, then N=2¹⁶=65,536, $\mathcal{X}_{LSB}=15.25\mu V$

 C_2

 C_3

 C_4

 C_5

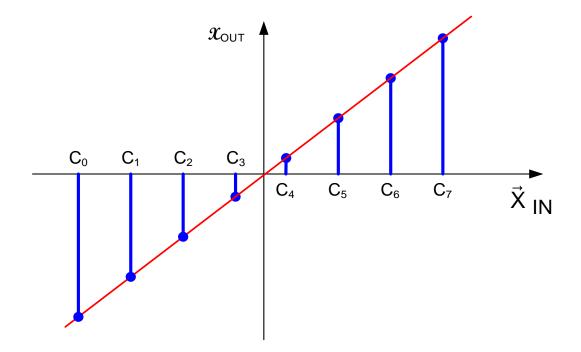
 C_6

 C_7

D/A Converters \vec{x}_{IN}



An alternate ideal 3-bit DAC

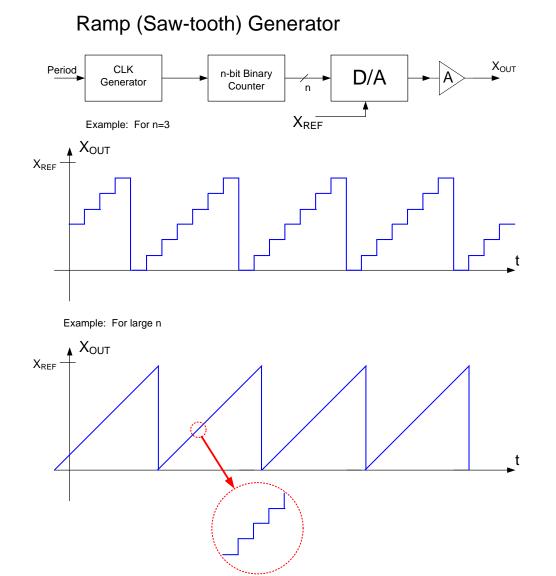


Irrespective of which form is considered, the increment in the output for one Boolean bit change in the input is \mathcal{X}_{LSB} and the total range is 1LSB less than \mathcal{X}_{REF}

Applications of DACs

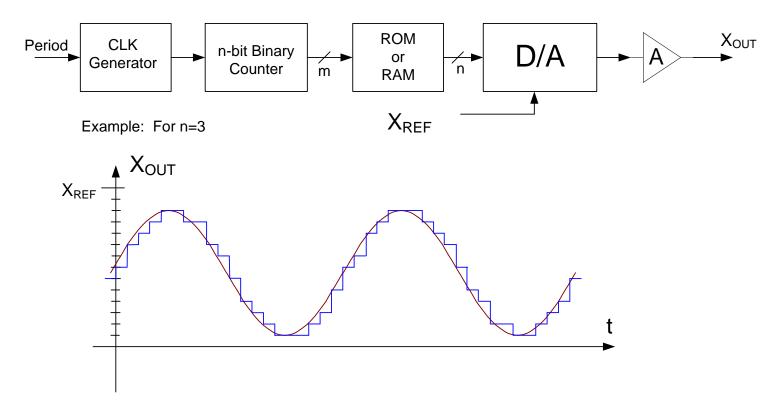
- Waveform Generation
- Voltage Generation
- Analog Trim or Calibration
- Industrial Control Systems
- Feedback Element in ADCs

Waveform Generation with DACs



Waveform Generation with DACs

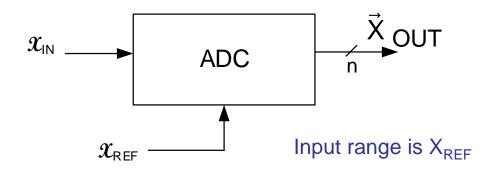
Sine Wave Generator



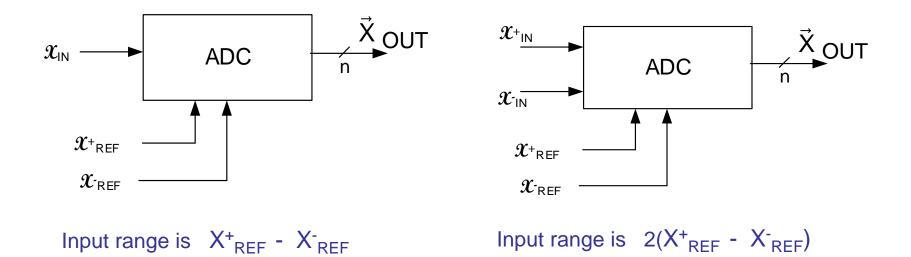
Distortion of the desired waveforms occurs due to both time and amplitude quantization

Often a filter precedes or follows the buffer amplifier to smooth the output waveform

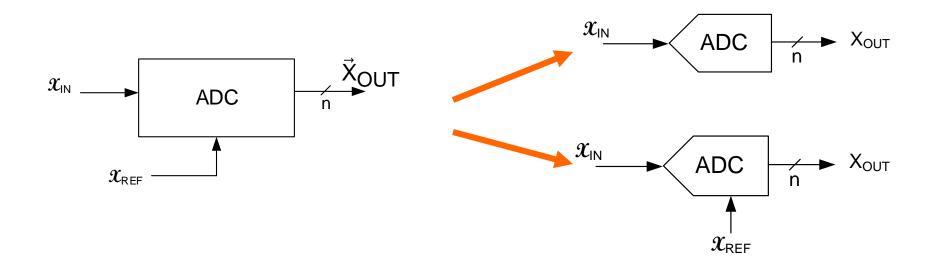
Basic structure:



Basic structure with differential inputs/references:



Notation:





 $\vec{X}_{OIJT} = < d_{n-1}, d_{n-2}, \dots d_{0} >$

d₀ is the Least Significant Bit (LSB)

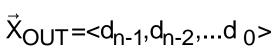
d_{n-1} is the Most Significant Bit (MSB)

Note: some authors use different index notation

An Ideal ADC is characterized at low frequencies by its static performance

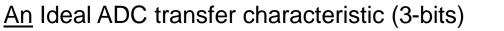
ADC

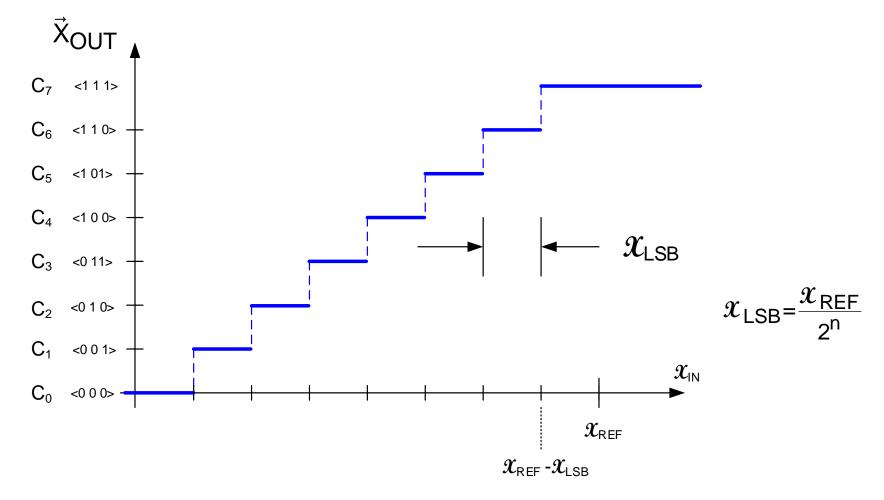
 $\mathfrak{X}_{\mathsf{IN}}$



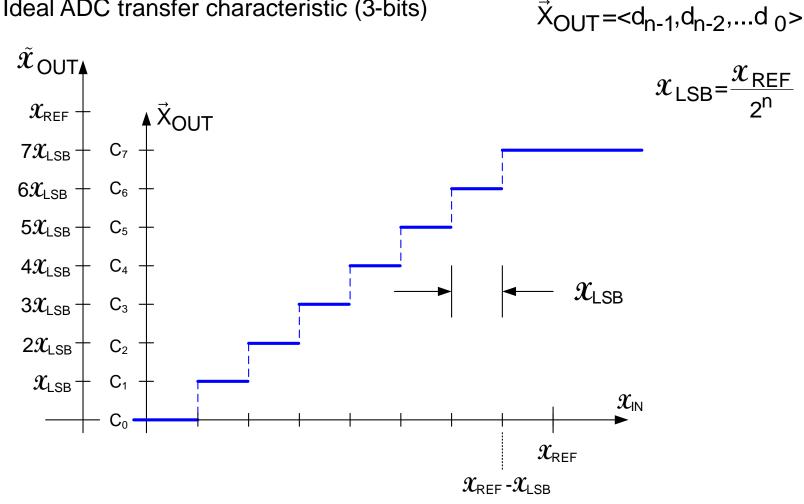
'n

 $\boldsymbol{X}_{\text{OUT}}$





An Ideal ADC transfer characteristic (3-bits)

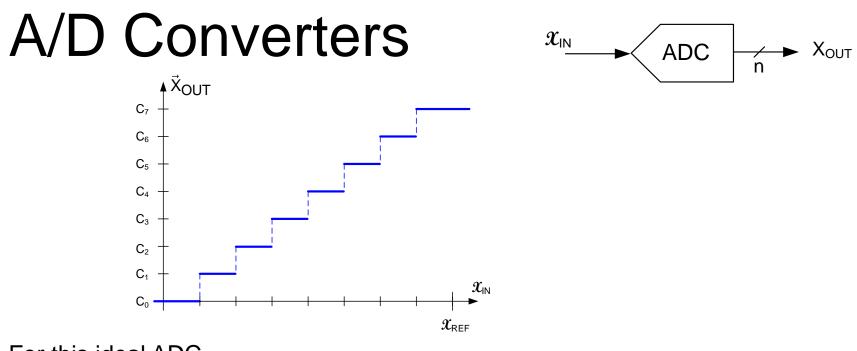


 $\mathfrak{X}_{\mathsf{IN}}$

ADC

 X_{OUT}

The second vertical axis, labeled $\hat{\mathcal{X}}_{OUT}$, is the interpreted value of \vec{X}_{OUT}



For this ideal ADC

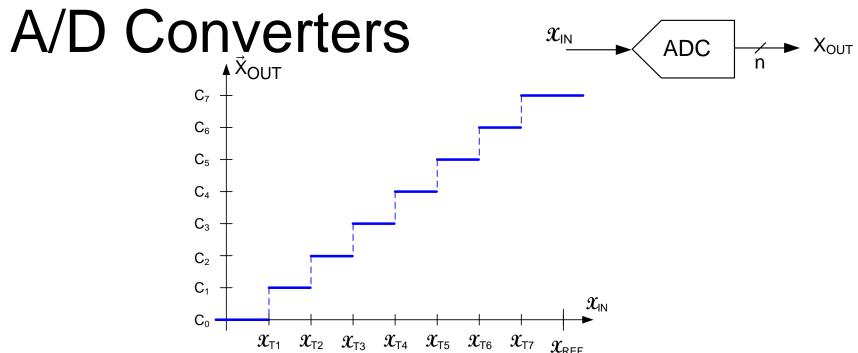
$$\mathscr{X}_{\mathsf{REF}}\left(\frac{d_{n-1}}{2} + \frac{d_{n-2}}{4} + \frac{d_{n-3}}{8} + \dots + \frac{d_1}{2^{n-1}} + \frac{d_0}{2^n}\right) = \mathscr{X}_{\mathsf{IN}} + \varepsilon$$

where ε is small (typically less than 1LSB)

$$\mathscr{X}_{\mathsf{REF}} \sum_{j=1}^{\mathsf{n}} \frac{\mathsf{d}_{\mathsf{n}}}{2^{\mathsf{j}}} = \mathscr{X}_{\mathsf{IN}} + \varepsilon$$

- Number of bins gets very large for n large
- Spacing between break points is $\mathcal{X}_{\text{REF}}/2^n$ and gets very small for n large

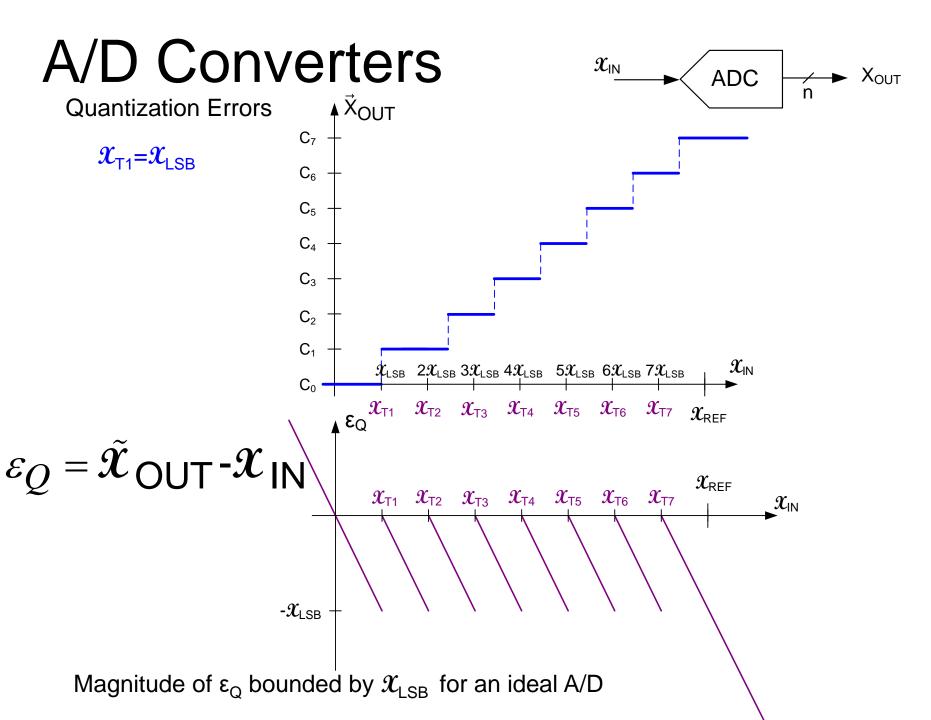
 ϵ is the **quantization error** and is inherent in any ADC

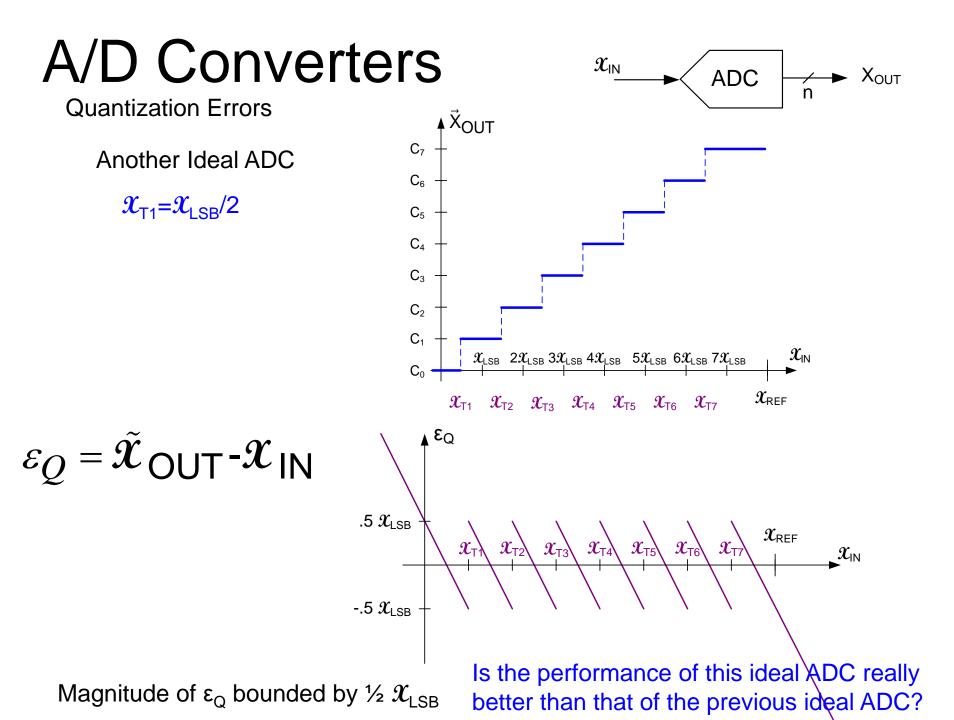


Transition Points

- Actual values of \mathcal{X}_{IN} where transitions occur are termed <u>transition points</u> or <u>break points</u>
- For an ideal n-bit ADC, there are 2ⁿ-1 transition points
- Ideally the transition points are all separated by 1 LSB -- $X_{LSB} = X_{REF}/2^n$
- Ideally the transition points are uniformly spaced
- In an actual ADC, the transition points will deviate a little from their ideal location Labeling Convention:

We will define the transition point X_{Tk} to be the break point where the transition in the code output to code C_k occurs. This seemingly obvious ordering of break points becomes ambiguous, though, when more than one break points cause a transition to code C_k which can occur in some nonideal ADCs



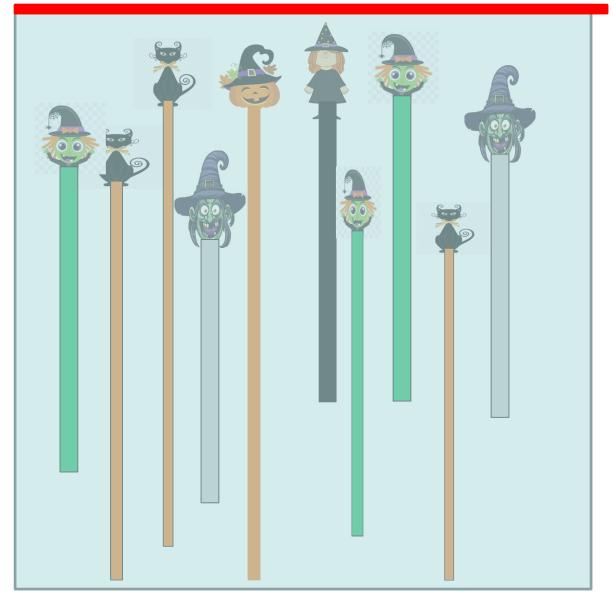




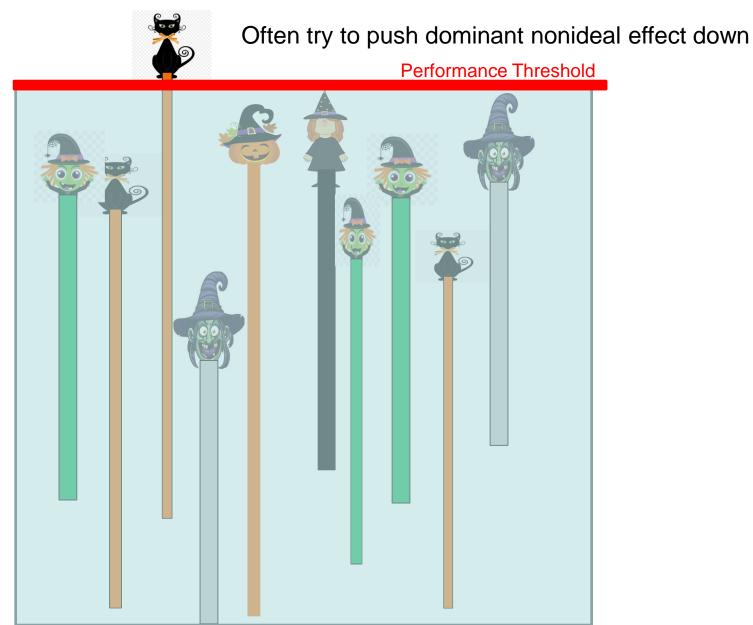
- Large number of different circuits have been proposed for building data converters
- Often a dramatic difference in <u>performance</u> from one structure to another
- Performance of almost all structures are identical if ideal components are used
- Much of data converter design involves identifying the problems associated with a given structure and figuring out ways to reduce the effects of these problems
- Critical that all problems that are significant be identified and solved
- Many of the problems are statistical in nature and implications of not solving problems are in a yield loss that may be dramatic

Ideally all performance limitations below performance threshold

Performance Threshold

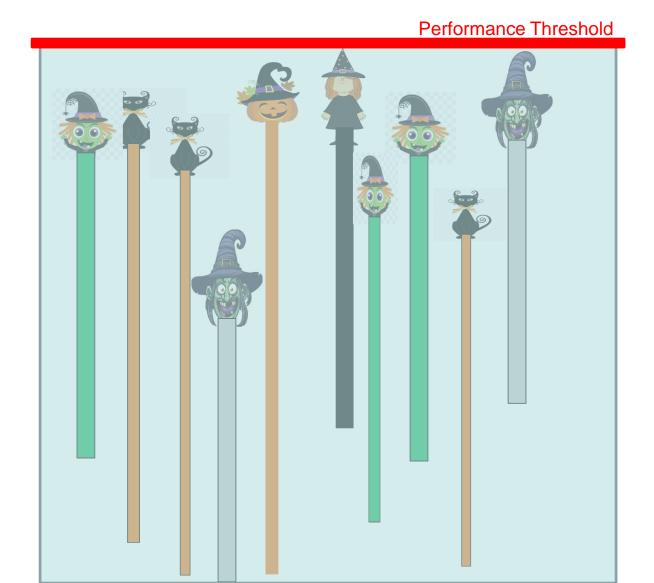


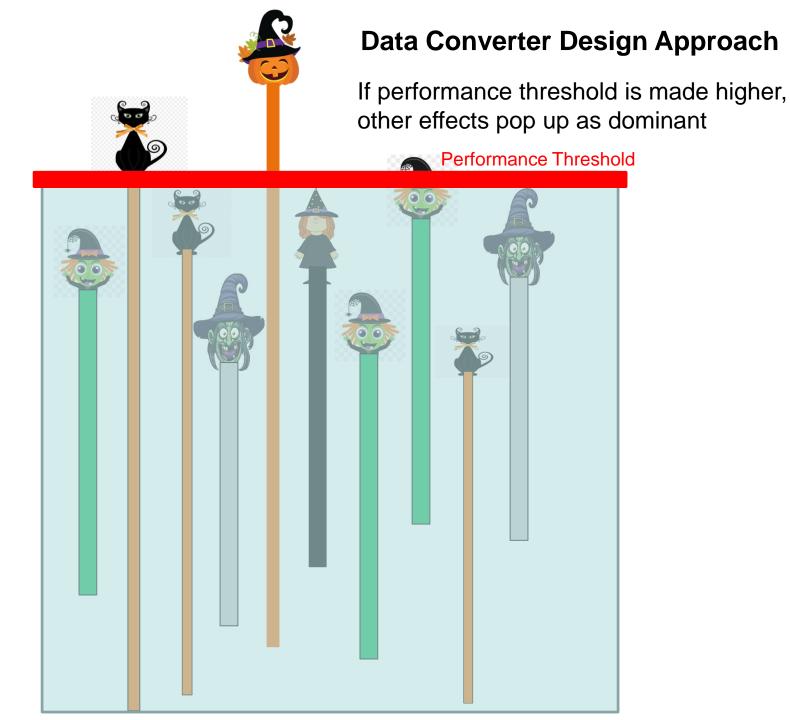
Often one or two nonideal effects above performance threshold



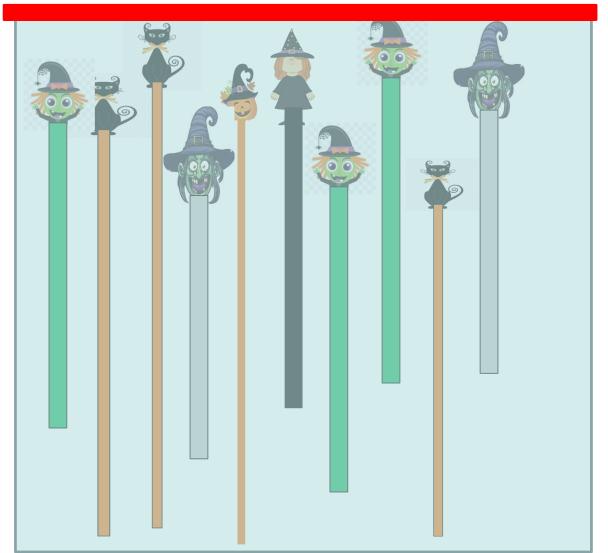
Often one or two nonideal effects above performance threshold

Often try to push dominant nonideal effect down



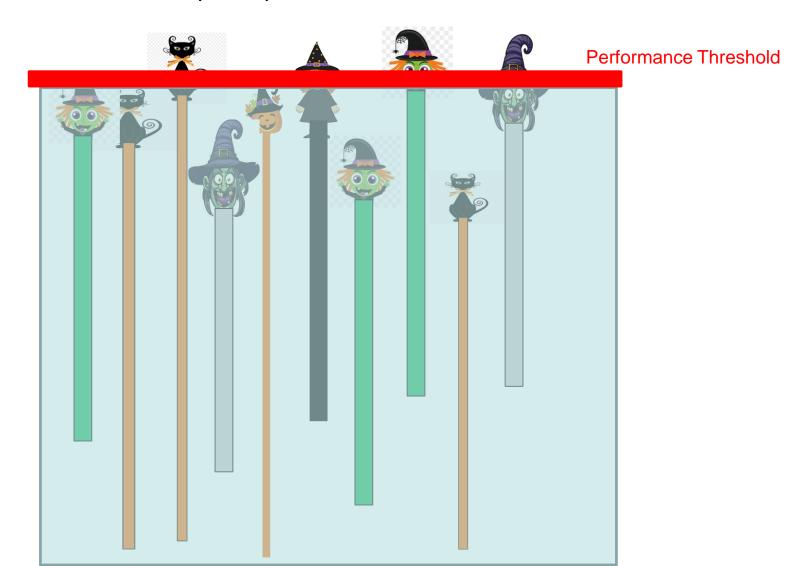


Push them down too



Performance Threshold

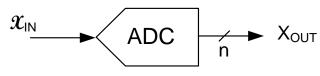
Ultimately lowering (enhancing) performane threshold makes it difficult to further improve performance





Strategy for discussing data converters

- Briefly look at some different data converter architectures
- Detailed discussion of performance parameters for data converters
- More detailed discussion of data converter architectures





Nyquist Rate

Flash Charge Redistribution Pipeline Two-step and Multi-Step Interpolating Algorithmic/Cyclic Successive Approximation (Register) SAR Single Slope / Dual Slope Subranging Folded Interleaved

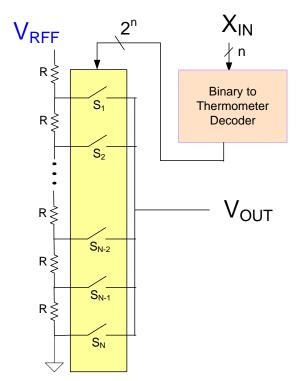
Current Steering R-string Charge Redistribution Algorithmic R-2R (ladder) Pipelined Subranging

Over-Sampled (Delta-Sigma)

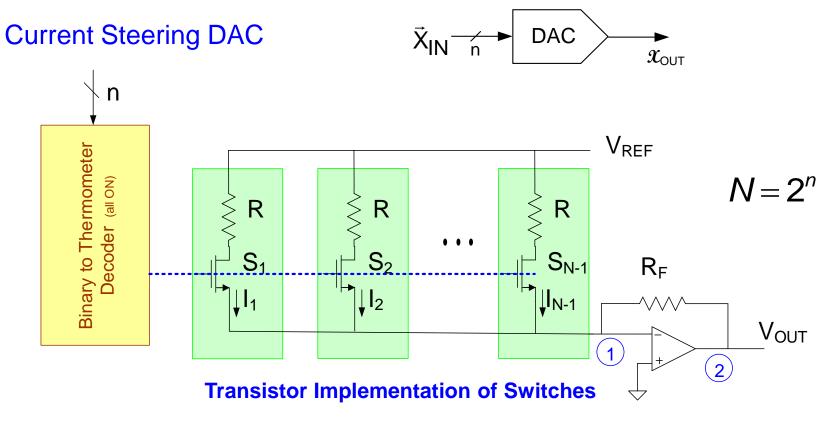
Discrete-time First-order/Higher Order Continuous-time Discrete-time First-order/Higher Order Continuous-time

R-String DAC

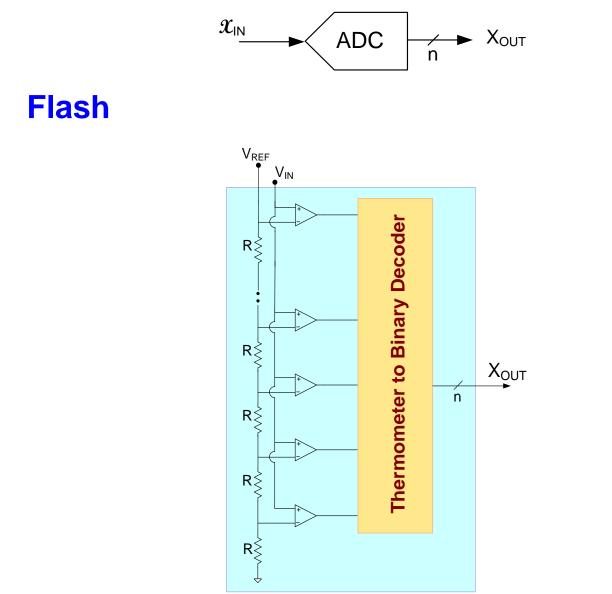




Basic R-String DAC including Logic to Control Switches

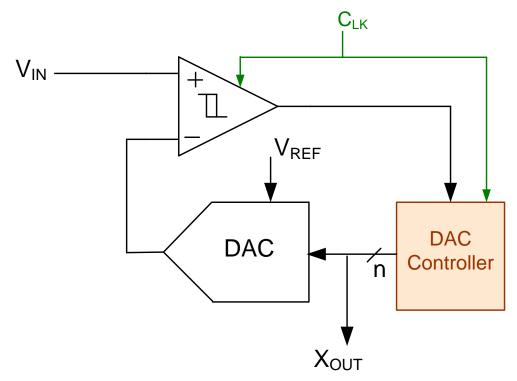


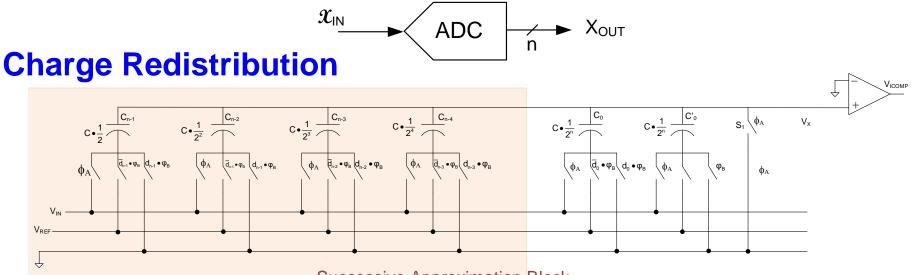
Assume k switches are on 0<k<N-1 as determined by digital input code





Successive Approximation Register (SAR)





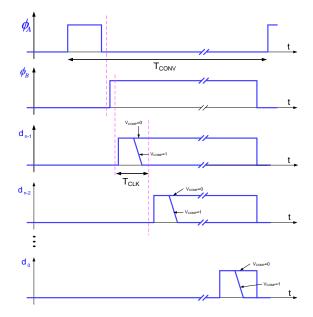
Successive Approximation Block

Redistribute charge with switches to drive Vx to 0

$$Q_{SAM} = V_{IN} \left(\sum_{i=0}^{n-1} C_i + \left[C_0 \right] \right) = V_{IN} \left(\sum_{i=0}^{n-1} \frac{C}{2^{n-i}} + \left[\frac{C}{2^n} \right] \right) = V_{IN} C$$
$$Q_{REDIS} = V_{REF} \sum_{i=0}^{n-1} d_i \frac{C}{2^{n-i}}$$

 $Q_{SAM} = Q_{REDIS}$

$$V_{REF} \sum_{i=0}^{n-1} d_i \frac{C}{2^{n-i}} = V_{IN}C$$
$$V_{IN} = V_{REF} \sum_{i=0}^{n-1} \frac{d_i}{2^{n-i}}$$



- Many more data converter architectures have been proposed
- Many are some variant of those listed above
- Recall: All typically are perfect if components are ideal
- The major nonideal effects are usually due to one of fourissues:
 - Matching performance is not acceptable
 - Speed is limited by parasitics
 - Device nonlinearities
 - Noise
- Most data converter design involves sequentially identifying dominant nonideal effect and developing ways to lower it
- Important to observe methods for mitigating nonideal effects as they are often used repeatedly
- With data converter design, "the devil is in the detail"

Performance Characterization of Data Converters



- A very large number of parameters (2ⁿ) characterize the static performance of an ADC!
- And even more parameters needed to characterize the dynamic performance of an ADC
- A large (but much smaller) number of parameters are invariably used to characterize a data converter
- Performance parameters of interest depend strongly on the application
- Very small number of parameters of interest in many/most applications
- "Catalog" data converters are generally intended to satisfy a wide range of applications and thus have much more stringent requirements placd on their performance
- Custom application-specific data converter will generally perform much better than a "catalog" part in the same application



Stay Safe and Stay Healthy !

End of Lecture 24